

# AUIRF3805/S/L

### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.051		V/°C	Reference to 25°C, $I_D = 1mA$
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		2.6	3.3	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A ④**
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
gfs	Forward Trans conductance	75			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 75A**
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20	μA	V <sub>DS</sub> =55V, V <sub>GS</sub> = 0V
				250		V <sub>DS</sub> =55V,V <sub>GS</sub> = 0V,T <sub>J</sub> =125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage			200	-	V <sub>GS</sub> = 20V
				-200		V <sub>GS</sub> = -20V

### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

-		-			
Q <sub>g</sub>	Total Gate Charge	 190	290		I <sub>D</sub> = 75A**
Q <sub>gs</sub>	Gate-to-Source Charge	 52		nC	$V_{DS} = 44V$
Q <sub>gd</sub>	Gate-to-Drain Charge	 72			V <sub>GS</sub> = 10V④
t <sub>d(on)</sub>	Turn-On Delay Time	 150			$V_{DD} = 28V$
t <sub>r</sub>	Rise Time	 20		20	I <sub>D</sub> = 75A**
t <sub>d(off)</sub>	Turn-Off Delay Time	 93		ns	R <sub>G</sub> = 2.6Ω
t <sub>f</sub>	Fall Time	 87			V <sub>GS</sub> = 10V ④
L <sub>D</sub>	Internal Drain Inductance	 4.5		nH	Between lead, 6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance	 7.5			from package and center of die contact
C <sub>iss</sub>	Input Capacitance	 7960			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	 1260			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance	 630		~	f = 1.0MHz, See Fig. 5
C <sub>oss</sub>	Output Capacitance	 4400		pF	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance	 980			$V_{GS} = 0V, V_{DS} = 44V f = 1.0MHz$
C <sub>oss eff.</sub>	Effective Output Capacitance	 1550			$V_{GS}$ = 0V, $V_{DS}$ = 0V to 44V

#### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			210①		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			890		integral reverse
$V_{SD}$	Diode Forward Voltage			1.3	V	T <sub>J</sub> = 25°C,I <sub>S</sub> = 75A**,V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time		36	54	ns	T <sub>J</sub> = 25°C ,I <sub>F</sub> = 75A**, V <sub>DD</sub> = 28V
Q <sub>rr</sub>	Reverse Recovery Charge		47	71	nC	di/dt = 100A/µs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic	turn-or	n time is	negligil	ble (turn-on is dominated by $L_{S}+L_{D}$ )

Notes:

- Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 160A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ③ This value determined from sample failure population, starting  $T_J = 25^{\circ}C$ , L = 0.23mH,  $R_G = 25\Omega$ ,  $I_{AS} = 75A$ ,  $V_{GS} = 10V$ .
- ④ Pulse width  $\leq$  1.0ms; duty cycle  $\leq$  2%.
- $\odot$  C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- ⑥ Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑦ This is only applied to TO-220AB package.
- It is applied to D<sup>2</sup>Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- (9)  $R_{\theta}$  is measured at T<sub>J</sub> of approximately 90°C
- TO-220 device will have an Rth value of 0.45°C/W.
- \*\* All AC and DC test condition based on old Package limitation current = 75A.

2



тор

BOTTOM

≤ 60µs PULSE WIDTH Tj = 175°C | | | | | | |

10

VGS 15V 10V 8.0V 7.0V 6.0V

5.5V 5.0V 4.5V

100

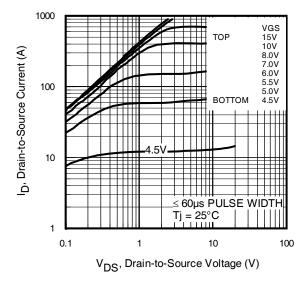


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

V<sub>DS</sub>, Drain-to-Source Voltage (V)

.5\

1

1000

100

10

0.1

I<sub>D</sub>, Drain-to-Source Current (A)

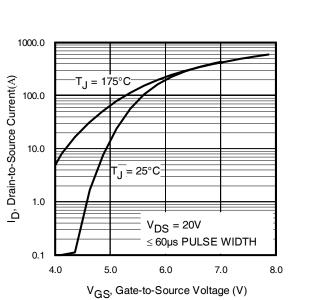


Fig. 3 Typical Transfer Characteristics



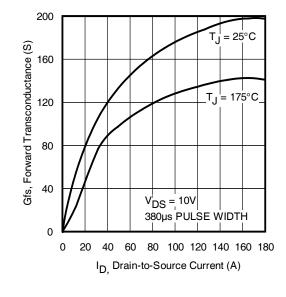
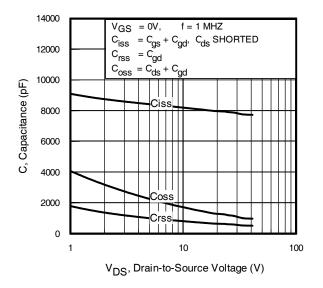
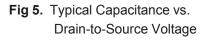
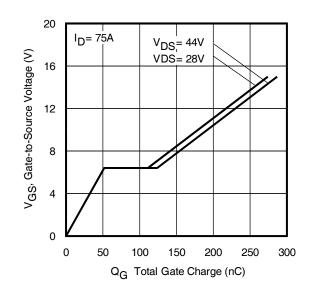


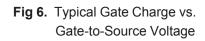
Fig. 4 Typical Forward Transconductance vs. Drain Current

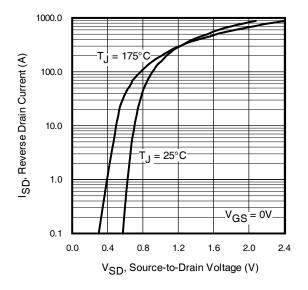














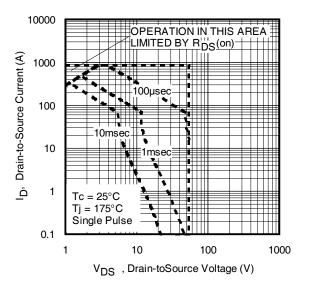


Fig 8. Maximum Safe Operating Area



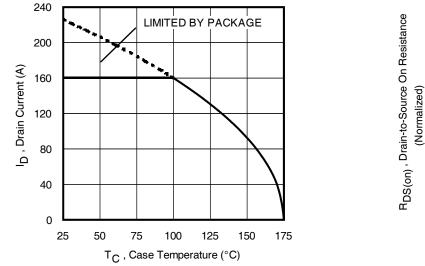
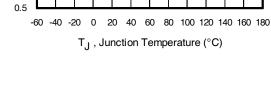


Fig 9. Maximum Drain Current vs. Case Temperature

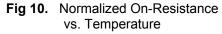


2.0

1.5

1.0

 $\frac{I_{D}}{V_{GS}} = \frac{75A}{10V}$ 



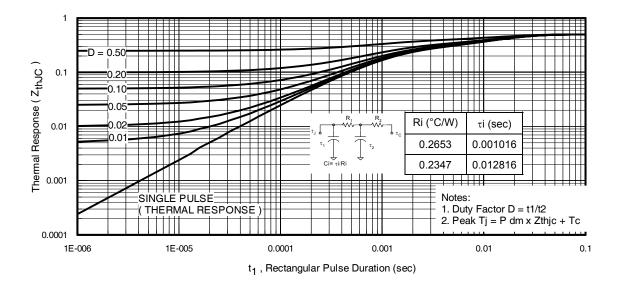


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

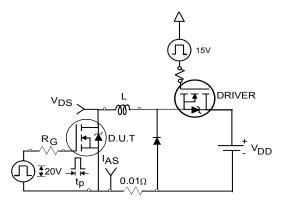


Fig 12a. Unclamped Inductive Test Circuit

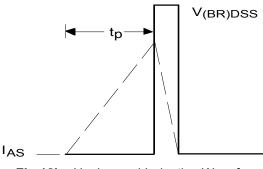
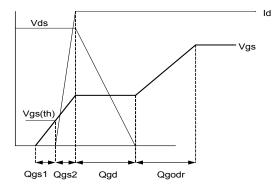
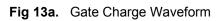


Fig 12b. Unclamped Inductive Waveforms





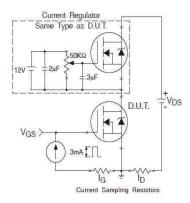


Fig 13b. Gate Charge Test Circuit

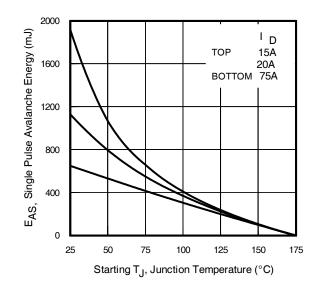


Fig 12c. Maximum Avalanche Energy vs. Drain Current

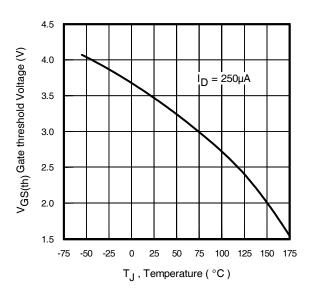


Fig 14. Threshold Voltage vs. Temperature



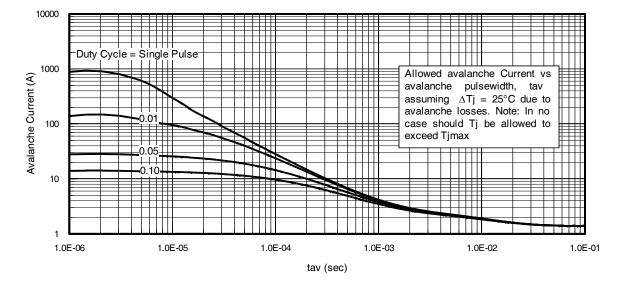
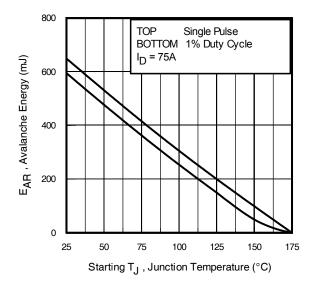
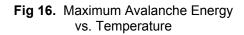


Fig 15. Typical Avalanche Current vs. Pulse width





#### Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).
  - tav = Average time in avalanche.
  - D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} \textbf{P}_{D \;(ave)} &= 1/2 \; ( \; 1.3 \cdot \textbf{BV} \cdot \textbf{I}_{av}) = \Delta T / \; \textbf{Z}_{th JC} \\ \textbf{I}_{av} &= 2 \Delta T / \; \textbf{[} 1.3 \cdot \textbf{BV} \cdot \textbf{Z}_{th} \textbf{]} \\ \textbf{E}_{AS \;(AR)} &= \textbf{P}_{D \;(ave)} \cdot \textbf{t}_{av} \end{split}$$

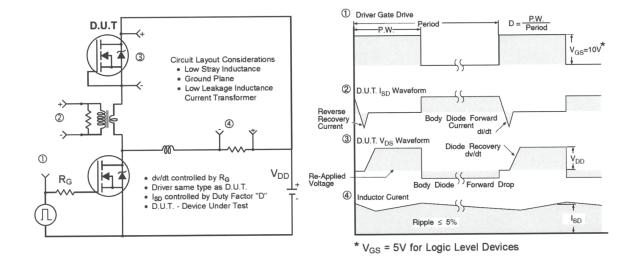


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

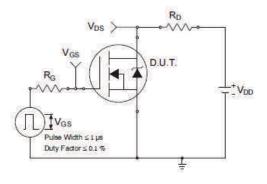


Fig 18a. Switching Time Test Circuit

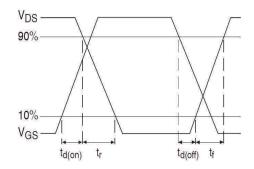
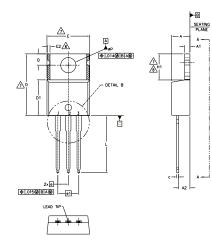


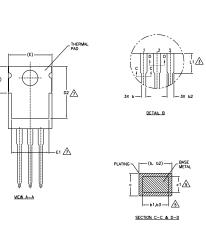
Fig 18b. Switching Time Waveforms



# AUIRF3805/S/L

#### TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994. 1.-
- 2.-
- 3 -
- DIMENSIONING AND TOLERANGUNG AS FER ASME 114.5 MF 1994. DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS] LEAD DIMENSION AND FINISH UNCONTROLLED IN L1. DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE 4.-MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- <u>/5.-</u> DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 6.-CONTROLLING DIMENSION : INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1 7. – 8.-
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- UTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE. 9.-

	DIMENSIONS				
SYMBOL	MILLIMETERS		INC		
	MIN.	MAX.	MIN.	MAX.	NOTES
A	3.56	4.83	.140	.190	
A1	1.14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
с	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
е	2.54	BSC	.100	BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
øР	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	
					•

LEAD ASSIGNMENTS

<u>HEXFET</u> 1.- GATE 2.- DRAIN 3.- SOURCE

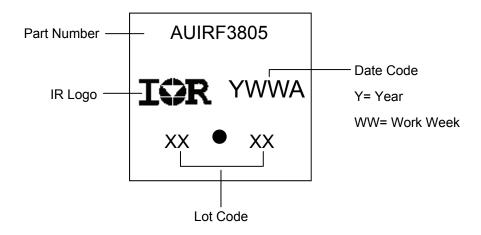
IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

DIODES

1.- ANODE 2.- CATHODE 3.- ANODE

#### **TO-220AB Part Marking Information**



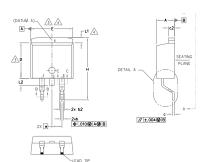
TO-220AB package is not recommended for Surface Mount Application.



Ψ

# AUIRF3805/S/L

# D<sup>2</sup>Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994

2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

 ADMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL

 NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED

 AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.

- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

	B	MIL
H A	L	MIN
PLATING	А	4.0
	A1	0.0
	b	0.5
(b, b2)	b1	0.5
SCALE: NONE	b2	1.14
	b3	1.14
H DETAIL "A"	С	0.38
ROTATED 90° CW SCALE 8:1	с1	0.3
	c2	1.14
SEATING PLANE	D	8.3
	D1	6.8
	E	9.6
	E1	6.2

S Y	DIMENSIONS				
M B O	MILLIMETERS		INC	O T E S	
L	MIN.	MAX.	MIN.	MAX.	E S
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
Е	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	-	.066	4
L2	_	1.78	-	.070	
L3	0.25	BSC	.010	BSC	

# LEAD ASSIGNMENTS

 LODES

 1.- ANOSE (TWO DIE) / OPEN (ONE DIE)

 4.- CATHODE

 3.- ANODE

 HEXFEI

 I.- GATE

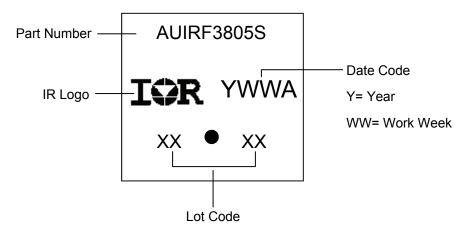
 1.- GATE

 2. 4.- DRAIN

 3.- SOURCE

 3.- SOURCE

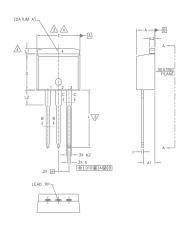
### D<sup>2</sup>Pak (TO-263AB) Part Marking Information

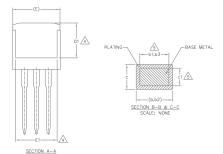




# AUIRF3805/S/L

### TO-262 Package Outline (Dimensions are shown in millimeters (inches)





NOTES

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 2.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

#### LEAD ASSIGNMENTS

IGBTS, COPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

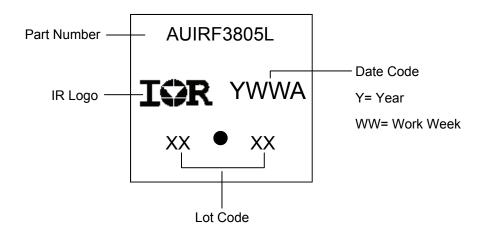
HEXFET DIODES

- 1.- ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.- CATHODE 3.- ANODE 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4.- DRAIN



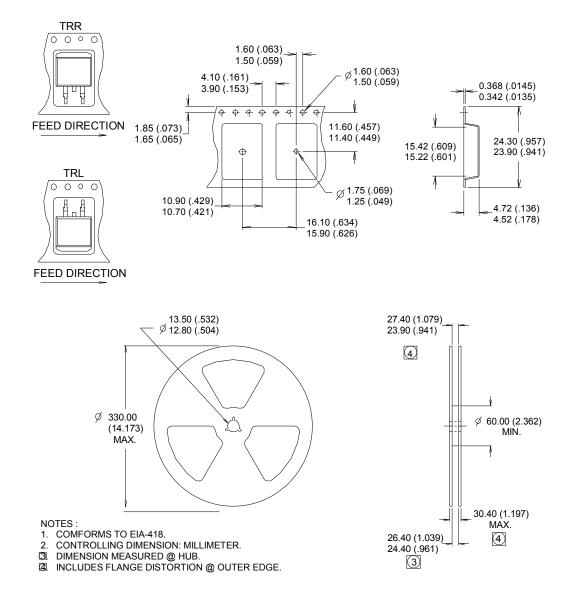
DIMENSIONS N O T M B O MILLIMETERS INCHES MIN. MAX. MIN. MAX. 4.83 А 4.06 160 190 Α1 2.03 3.02 .119 .080. b 0.51 0.99 .039 b1 0.51 0.89 .035 5 1.78 1.14 .045 1,14 1.73 .045 068 5 b.3 0.38 0.74 С .015 .029 0.38 0.58 5 c2 1.14 1.65 .045 .065 8.38 D 9.65 .380 3 .330 .270 6.86 4 Е 9.65 10.67 .380 .420 3,4 E1 6.22 245 4 2.54 BSC BSC е 13.46 14.10 530 L1 1.65 065 4 3.56 3.71 140 .146

#### **TO-262 Part Marking Information**





## D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))



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### **Qualification Information**

		Automotive				
		(per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
		TO-220AB	N/A			
Moisture	Moisture Sensitivity Level		MSL1, 260°C			
		D <sup>2</sup> -Pak	WOL 1, 200 C			
	Machine Madel	Class M4 (+/-425V) <sup>†</sup>				
	Machine Model	AEC-Q101-002				
		Class H3A (+/-4000V) <sup>†</sup>				
ESD	Human Body Model	AEC-Q101-001				
		Class C5 (+/-1000V) <sup>†</sup>				
	Charged Device Model		AEC-Q101-005			
RoHS Compliant		Yes				

† Highest passing voltage.

#### **Revision History**

Date	Comments
9/30/2015	<ul> <li>Updated datasheet with corporate template</li> <li>Corrected ordering table on page 1.</li> </ul>
8/23/2017	Corrected part marking on pages 9,10,11.

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